

**Notice of References Cited**

Application/Control No.

10/593,424

Applicant(s)/Patent Under  
Reexamination  
RITTER ET AL.

Examiner

HAI PHAN

Art Unit

2614

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,335,011	08-1994	Addeo et al.	348/14.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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